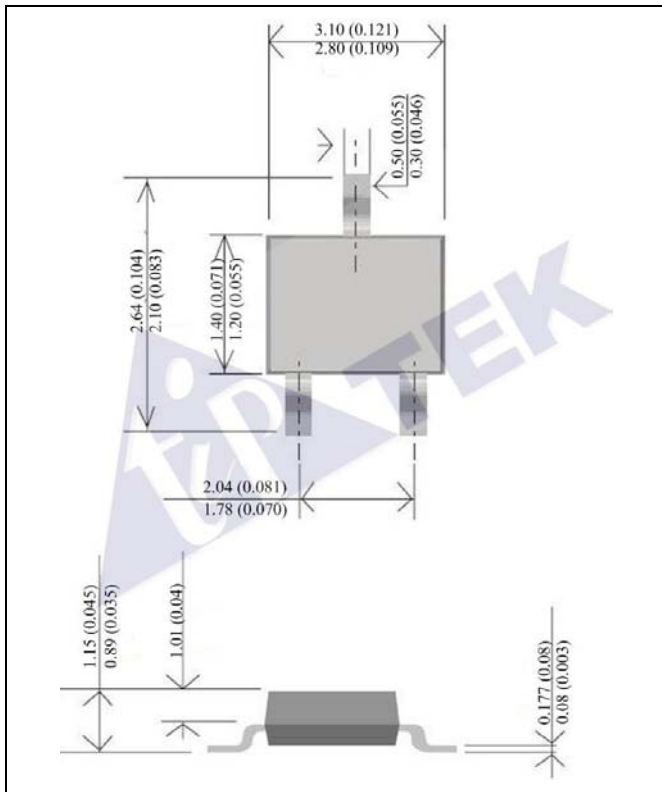


## N-CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR



CASE : SOT-23

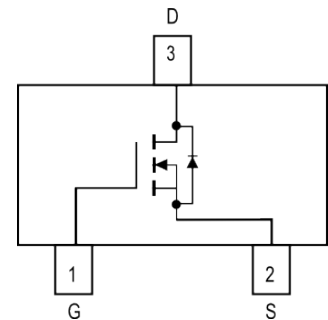
DIMENSIONS IN MILLIMETERS AND (INCHES)

### FEATURES

- N-CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR, DESIGNED FOR HIGH SPEED PULSE AMPLIFIER AND DRIVE APPLICATION, WHICH IS MANUFACTURED BY THE N-CHANNEL DMOS PROCESS.
- BOTH PB FREE AND HALOGEN FREE PRODUCT ARE AVAILABLE

### MECHANICAL DATA

- CASE: SOT-23
- TERMINALS : SOLDERABLE PER MIL-STD-202, METHOD208
- APPROX. WEIGHT:0.008 GRAM
- Pb Free: 2SK801  
Halogen Free: 2SK801-H



### ABSOLUTE MAXIMUM RATINGS

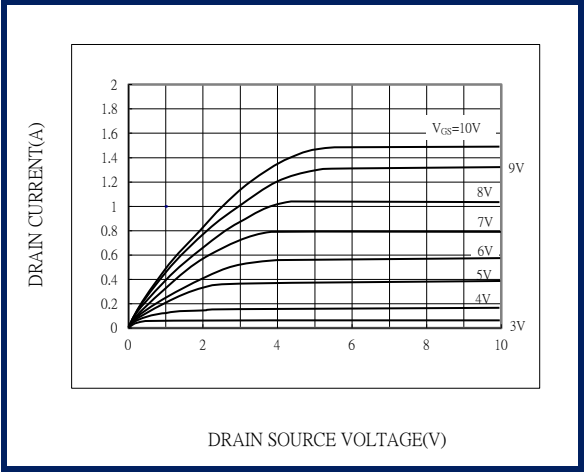
RATINGS AT 25°C AMBIENT TEMPERATURE UNLESS OTHERWISE SPECIFIED.			
PATING	SYMBOL	VALUE	UNITS
DRAIN-SOURCE VOLTAGE	$V_{DSS}$	60	V
DRAIN-GATE VOLTAGE( $R_{GS}=1.0M\Omega$ )	$V_{DGR}$	60	V
GATE-SOURCE VOLTAGE - CONTINUOUS	$V_{GSS}$	$\pm 20$	V
GATE-SOURCE VOLTAGE - NON-REPETITIVE ( $t_p < 50\mu s$ )	$V_{GSM}$	$\pm 40$	V
MAXIMUM DRAIN CURRENT-CONTINUE	$I_D$	310	mA
MAXIMUM DRAIN CURRENT-PULSE ( $t < 10\mu s$ )	$I_{DM}$	1200	mA
MAXIMUM POWER DISSIPATION DERATING <sup>(NOTE 2)</sup>	$P_D$	225	mW
THERMAL RESISTANCE – JUNCTION TO AMBIENT <sup>(NOTE 2)</sup>	$R_{\theta JA}$	556	$^{\circ}C/W$
MAXIMUM POWER DISSIPATION DERATING <sup>(NOTE 3)</sup>	$P_D$	300	mW
THERMAL RESISTANCE – JUNCTION TO AMBIENT <sup>(NOTE 3)</sup>	$R_{\theta JA}$	417	$^{\circ}C/W$
OPERATING AND STORAGE JUNCTION TEMPERATURE RANGE	$T_J; T_{STG}$	- 55 TO +150	$^{\circ}C$

- NOTE: 1. THE POWER DISSIPATION OF THE PACKAGE MAY RESULT IN A LOWER CONTINUOUS DRAIN CURRENT.  
 2. FR-5 = 1.0x0.75x0.062 in.  
 3. ALUMINA = 0.4x0.3x0.025 in 99.5% ALUMINA.

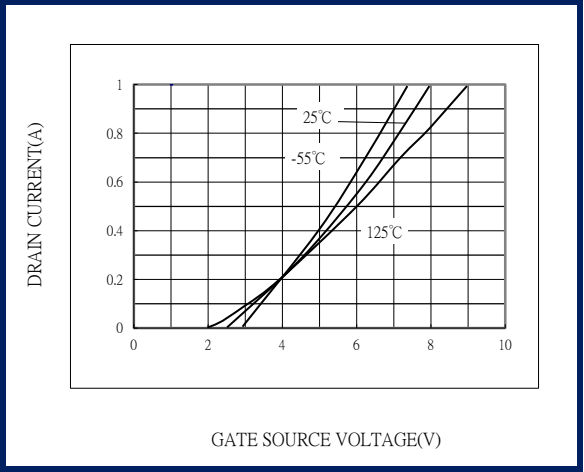
**ELECTRICAL CHARACTERISTICS**

<b>ELECTRICAL CHARACTERISTICS (AT T<sub>A</sub> =25°C UNLESS OTHERWISE NOTED)</b>						
CHARACTERISTIC	SYMBOL	MIN	TYP	MAX	UNITS	
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =10μA	V <sub>(BR)DSS</sub>	60	–	–	V
Zero Gate Voltage Drain	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	I <sub>DSS</sub>	–	–	1.0	μA
	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C				500	
Gate-Body Leakage, Forward (V <sub>DS</sub> =0, V <sub>GS</sub> =20V)		I <sub>GSSF</sub>	–	–	+100	nA
Gate-Body Leakage, Reverse (V <sub>DS</sub> =0, V <sub>GS</sub> =-20V)		I <sub>GSSR</sub>	–	–	-100	nA
<b>ON CHARACTERISTICS (NOTE 1)</b>						
Gate Threshold Voltage(V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA)		V <sub>GS(th)</sub>	1	1.8	2.2	V
Drain-Source On- Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =500mA	R <sub>DS(ON)</sub>	–	–	1.5	Ω
	V <sub>GS</sub> =5.0V, I <sub>D</sub> =50mA				1.7	
On-State Drain Current(V <sub>GS</sub> =10V, V <sub>DS</sub> ≥2V <sub>DS(ON)</sub> )		I <sub>D(ON)</sub>	500	–	–	mA
Static Drain-Source On-State Voltage	V <sub>GS</sub> =10V, I <sub>D</sub> =500mA	V <sub>DS(on)</sub>	–	–	3.75	V
	V <sub>GS</sub> =5.0V, I <sub>D</sub> =50mA				0.375	
<b>BODY-DRAIN DIODE RATINGS</b>						
Source Current Continuous		I <sub>S</sub>	–	–	-115	mA
Source Current Pulsed		I <sub>SM</sub>	–	–	-800	mA
Diode Forward Voltage (I <sub>S</sub> =115mA, V <sub>GS</sub> =0V)		V <sub>SD</sub>	–	–	-1.5	V
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, F=1.0MHz	C <sub>ISS</sub>	–	17	50	pF
Output Capacitance		C <sub>OSS</sub>	–	10	25	pF
Reverse Transfer Capacitance		C <sub>RSS</sub>	–	2.5	5	pF
Turn-On Time		V <sub>DD</sub> =25V, R <sub>L</sub> =50Ω, I <sub>D</sub> =500mA	t <sub>d(on)</sub>	–	7	20
Turn-Off Time	V <sub>GS</sub> =10V, R <sub>GEN</sub> =25Ω	t <sub>d(off)</sub>	–	11	40	ns

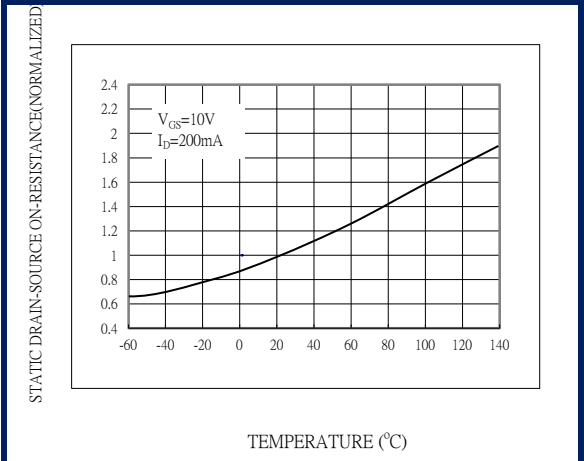
**NOTE: 1. Pulse Test: Pulse Width <300 us, Duty Cycle <2.0%.**



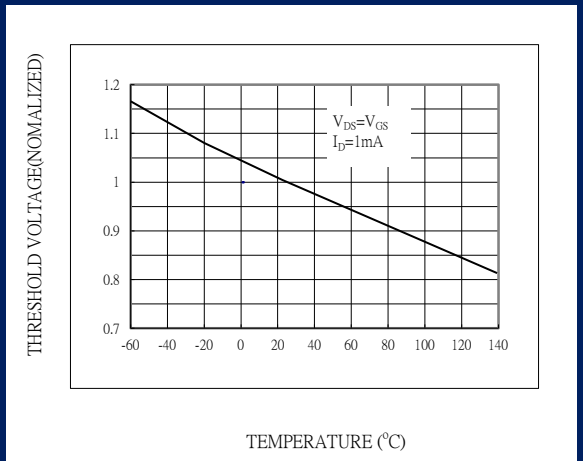
**Fig.1-OHMIC REGION**



**Fig.2-TRANSFER CHARACTERISTICS**



**Fig.3-DRAIN SOURCE ON-RESISTANCE VS. TEMPERATURE**



**Fig.4-GATE THRESHOLD VOLTAGE VS. TEMPERATURE**